International TOR Rectifier

IRF9Z34N

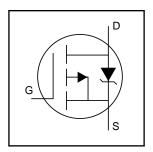
HEXFET® Power MOSFET

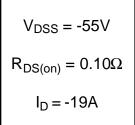
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- P-Channel
- Fully Avalanche Rated

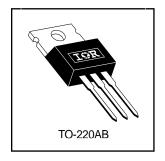
Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.







Absolute Maximum Ratings

	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ -10V	-19		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ -10V	-14	A	
I _{DM}	Pulsed Drain Current ①	-68		
P _D @T _C = 25°C	Power Dissipation	68	W	
	Linear Derating Factor	0.45	W/°C	
V_{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy②	180	mJ	
I _{AR}	Avalanche Current①	-10	A	
E _{AR}	Repetitive Avalanche Energy®	6.8	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	-5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		2.2	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

Electrical Characteristics @ $T_J = 25$ °C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	-55			V	$V_{GS} = 0V, I_{D} = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.05		V/°C	Reference to 25°C, I _D = -1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.10	Ω	V _{GS} = -10V, I _D = -10A ④
V _{GS(th)}	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
9 _{fs}	Forward Transconductance	4.2			S	$V_{DS} = 25V, I_{D} = -10A$
I	Drain-to-Source Leakage Current			-25		$V_{DS} = -55V, V_{GS} = 0V$
I _{DSS}	Diali-to-Source Leakage Current			-250	μA	$V_{DS} = -44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	IIA	V _{GS} = -20V
Qg	Total Gate Charge			35		I _D = -10A
Q _{gs}	Gate-to-Source Charge			7.9	nC	$V_{DS} = -44V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			16		V _{GS} = -10V, See Fig. 6 and 13 ④
t _{d(on)}	Turn-On Delay Time		13			$V_{DD} = -28V$
t _r	Rise Time		55			I _D = -10A
t _{d(off)}	Turn-Off Delay Time		30		ns	$R_G = 13\Omega$
t _f	Fall Time		41			$R_D = 2.6\Omega$, See Fig. 10 \oplus
1-	Internal Drain Inductance		4.5			Between lead,
L _D	internal Drain inductance		4.5		nH	6mm (0.25in.)
L _S	Internal Source Inductance		7.5		1111	from package
						and center of die contact
C _{iss}	Input Capacitance		620			V _{GS} = 0V
C _{oss}	Output Capacitance		280		pF	$V_{DS} = -25V$
C _{rss}	Reverse Transfer Capacitance		140			f = 1.0MHz, See Fig. 5

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			-19		MOSFET symbol
	(Body Diode)		-19	A	showing the	
I _{SM}	Pulsed Source Current				'''	integral reverse
	(Body Diode) ①	-	-68		p-n junction diode.	
V _{SD}	Diode Forward Voltage			-1.6	V	$T_J = 25^{\circ}C$, $I_S = -10A$, $V_{GS} = 0V$ ④
t _{rr}	Reverse Recovery Time		54	82	ns	$T_J = 25^{\circ}C, I_F = -10A$
Q _{rr}	Reverse RecoveryCharge		110	160	nC	di/dt = -100A/µs ④
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25$ °C, L = 3.6mH $R_G = 25\Omega$, $I_{AS} = -10$ A. (See Figure 12)
- $\label{eq:loss} \begin{array}{l} \mbox{(3)} \ \ I_{SD} \leq \mbox{-10A, di/dt} \leq \mbox{-290A/\mu s, V}_{DD} \leq V_{(BR)DSS}, \\ \mbox{T}_{J} \leq \mbox{175}^{\circ}C \end{array}$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.

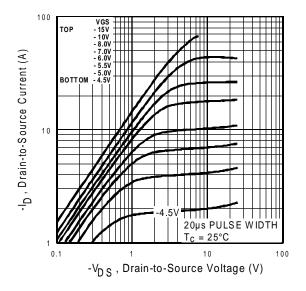


Fig 1. Typical Output Characteristics

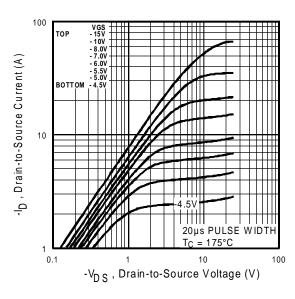


Fig 2. Typical Output Characteristics

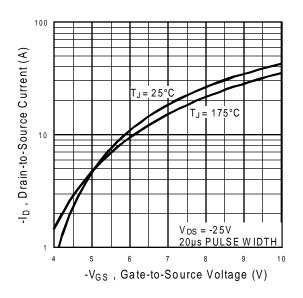


Fig 3. Typical Transfer Characteristics

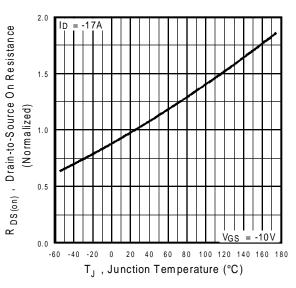


Fig 4. Normalized On-Resistance Vs. Temperature

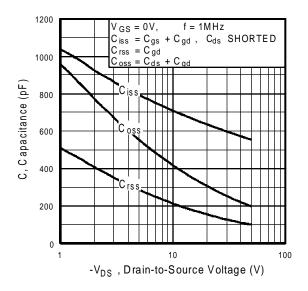


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

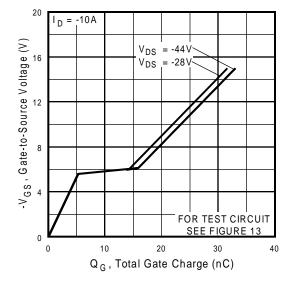


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

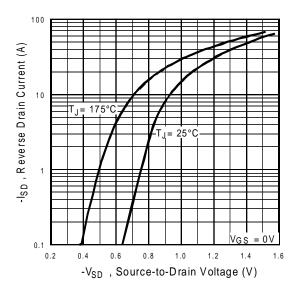


Fig 7. Typical Source-Drain Diode Forward Voltage

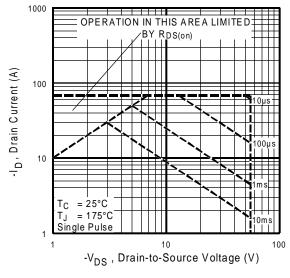


Fig 8. Maximum Safe Operating Area

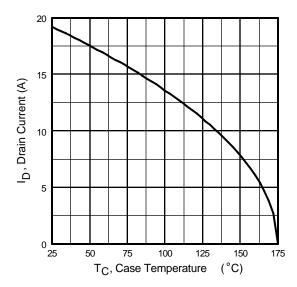


Fig 9. Maximum Drain Current Vs. Case Temperature

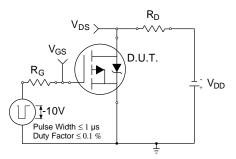


Fig 10a. Switching Time Test Circuit

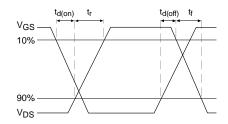


Fig 10b. Switching Time Waveforms

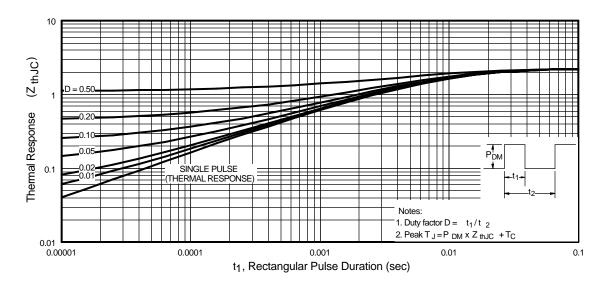


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

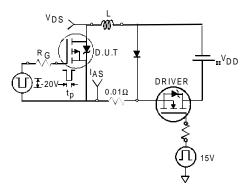


Fig 12a. Unclamped Inductive Test Circuit

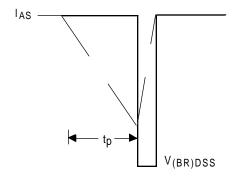


Fig 12b. Unclamped Inductive Waveforms

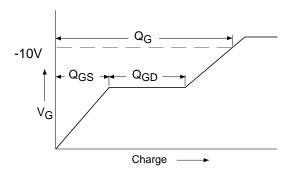


Fig 13a. Basic Gate Charge Waveform

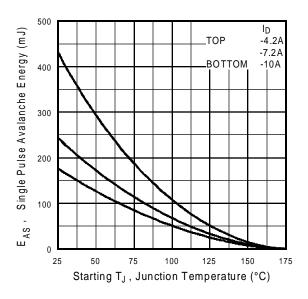


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

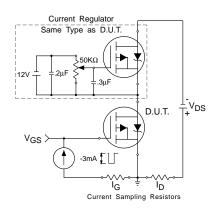
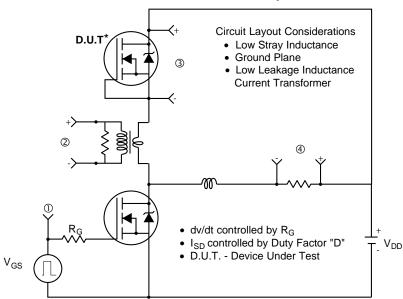
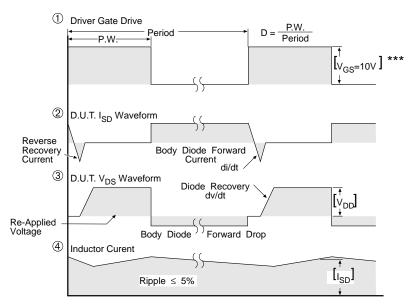


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



^{*} Reverse Polarity of D.U.T for P-Channel



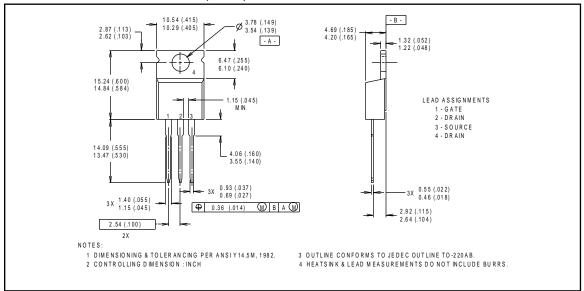
*** $V_{GS} = 5.0V$ for Logic Level and 3V Drive Devices

Fig 14. For P-Channel HEXFETS

Package Outline

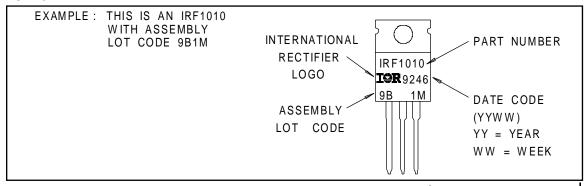
TO-220AB Outline

Dimensions are shown in millimeters (inches)



Part Marking Information

TO-220AB



International Rectifier

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http://www.irf.com/ Data and specifications subject to change without notice. 8/97

Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/